


Search Notes 	Application/Control No. 10600087	Applicant(s)/Patent Under Reexamination MARUYA, MAKOTO
	Examiner Chawan, Sheela C	Art Unit 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	144,154,	1/7/07	SCC
370	538,465,385,	1/7/07	SCC
348	42,145,169,143,144	1/7/07	SCC
351	57,158	1/7/07	SCC
124	87	1/7/07	SCC
345	440,427,428	5/11/07	SCC
382	154	"	"
348	42,144	"	"
345	427	"	"
ABOVE SEARCH UP- DATE.		"	"

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US-PGPUB,USPAT,EPO,JPO,DERWENT,IBM-TDB.	1/7/07	SCC
INVENTOR NAME SEARCH.	1/7/07	SCC
382/144,154.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	5/11/07	SCC
348/42,144.CCLS. "	"	"
345/427.CCLS. "	"	"
INTERFERENCE SEARCH, SEE SEARCH HISTORY PRINT OUT.	"	"
SEARCH IEEE OR INSPEC DATA BASE.	"	"

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	144,154	5/11/07	SCC
348	42,144	"	"
345	427	"	"